

INTERNATIONAL STANDARD



GROUP SAFETY PUBLICATION

**Safety requirements for electrical equipment for measurement, control, and laboratory use –
Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement**

IEC 61010-031:2022

<https://standards.iteh.ai/catalog/standards/sist/096f8d8f-4592-499a-a290-feead86a3a05/iec-61010-031-2022>



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COMMENTED VERSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE –

Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement

FOREWORD

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This commented version (CMV) of the official standard IEC 61010-031:2022 edition 3.0 allows the user to identify the changes made to the previous IEC 61010-031:2015+AMD1:2018 CSV edition 2.1. Furthermore, comments from IEC TC 66 experts are provided to explain the reasons of the most relevant changes, or to clarify any part of the content.

A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text. Experts' comments are identified by a blue-background number. Mouse over a number to display a pop-up note with the comment.

This publication contains the CMV and the official standard. The full list of comments is available at the end of the CMV.

IEC 61010-031 has been prepared by IEC technical committee 66: Safety of measuring, control and laboratory equipment. It is an International Standard.

It has the status of a group safety publication in accordance with IEC Guide 104.

This third edition cancels and replaces the second edition published in 2015, and Amendment 1:2018. IEC 61010-031 is a stand-alone standard.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the scope has been made succinct. General information from the scope of Edition 2 has been moved to a new Clause 4. Consequently, Clause 4 to Clause 8 of Edition 2 have been renumbered. Clause 9 of Edition 2 has been deleted;
- b) in Clause 2, normative references have been dated and new normative references have been added;
- c) in 3.1.4, the definition of PROBE TIP has been modified;
- d) in 4.1, there is no longer any differentiation between high voltage and low voltage probe assemblies. Type C probe assemblies have been merged with Type B probe assemblies;
- e) in 4.1 d) "Kelvin" probes have been added to the list of probe assemblies as a new Type E and a new Figure 5;
- f) in 4.1 e), probes for voltage measurement without electrical connection to conductors have been added to the list of probe assemblies as a new Type F and a new Figure 6;
- g) in 4.2.1, spread of fire is no longer considered as a HAZARD;
- h) Subclause 4.4.2.5 from Edition 2 has been deleted;
- i) Subclause 4.4.4.3 from Edition 2 has been deleted;
- j) in 5.4.4.1 consideration has been given to SPACINGS and impedance;
- k) in 6.1.1, removable parts of PROBE TIPS which bear markings are allowed;
- l) in 6.1.5, the voltage to be marked for MEASUREMENT CATEGORIES is the AC line-to-neutral or DC voltage;
- m) in 7.4.2, requirements for unmated CONNECTORS have been modified as follows:
 - 1) Table 2 has been modified and expanded,
 - 2) a calculation method for CLEARANCES of CONNECTORS above 20 kV has been defined,
 - 3) CREEPAGE DISTANCES have been aligned with CLEARANCES;
- n) in 7.4.3.1 and 7.4.3.5, requirements for IP2X PROBE TIPS with retractable sleeve have been added;
- o) in 7.4.3.2, PROBE TIPS are now applicable to non-contact probe assemblies;
- p) in 7.5.2.3.2, the values of Table 5 have been modified;
- q) in 7.6.2, voltage tests of CLEARANCES are done without humidity preconditioning;
- r) pre-treatments for rigidity test from Clause 10 of Edition 2 have been moved to 9.2;
- s) Subclause 11.1 of Edition 2 has been deleted;
- t) addition of an exception for Type E probe assembly in 13.2. Removable parts of PROBE TIPS which bear markings are allowed;
- u) Figure F.1 has been modified;
- v) Annex G has been added, for determination of CLEARANCES for Table 2;
- w) Annex H has been added, covering line-to-neutral voltages for common mains supply systems.

The text of this International Standard is based on the following documents:

Draft	Report on voting
66/770/FDIS	66/771/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts of the IEC 61010 series, published under the general title, *Safety requirements for electrical equipment for measurement, control, and laboratory use*, can be found on the IEC website.

In this document the following print types are used:

- requirements and definitions: in roman type;
- NOTES and EXAMPLES: in smaller roman type;
- *conformity and tests: in italic type;*
- terms used throughout this document which have been defined in Clause 3: SMALL ROMAN CAPITALS.

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SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL, AND LABORATORY USE –

Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement

1 ~~Scope and object~~ 1

~~1.1 Scope~~

~~1.1.1 Probe assemblies included in scope~~

This part of IEC 61010 specifies safety requirements for hand-held and hand-manipulated probe assemblies ~~of the types described below~~ for electrical test and measurement, and their related accessories. These probe assemblies are for non-contact 2 or direct electrical connection between a part and electrical test and measurement equipment. They ~~may~~ can be fixed to the equipment or be detachable accessories for the equipment.

This group safety publication focusing on safety essential requirements is primarily intended to be used as a product safety standard for the products mentioned in the scope, but is also intended to be used by technical committees in the preparation of publications for products similar to those mentioned in the scope of this group safety publication, in accordance with the principles laid down in IEC Guide 104 and ISO/IEC Guide 51.

One of the responsibilities of a technical committee is, wherever applicable, to make use of basic safety publications and/or group safety publications in the preparation of its publications. 3

<https://standards.iteh.ai/catalog/standards/sist/096f8d8f-4592-499a-a290-feead86a3a05/iec-61010-031-2022>

2 Normative references 4

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

~~IEC 60027 (all parts), Letter symbols to be used in electrical technology~~

IEC 60027-1:1992, *Letter symbols to be used in electrical technology – Part 1: General*
IEC 60027-1:1992/AMD1:1997
IEC 60027-1:1992/AMD2:2005

IEC 60027-2:2019, *Letter symbols to be used in electrical technology – Part 2: Telecommunications and electronics*

IEC 60027-4:2006, *Letter symbols to be used in electrical technology – Part 4: Rotating electric machines*

IEC 60529:1989, *Degrees of protection provided by enclosures (IP Code)*
IEC 60529:1989/AMD1:1999
IEC 60529:1989/AMD2:2013

IEC 61010-1:2010, *Safety requirements for electrical equipment for measurement, control, and laboratory use – Part 1: General requirements*
IEC 61010-1:2010/AMD1:2016

IEC 61180:2016, *High-voltage test techniques for low-voltage equipment – Definitions, test and procedure requirements, test equipment*

~~IEC 61180-1:1992, *High-voltage test techniques for low-voltage equipment – Part 1: Definitions, test and procedure requirements*~~

~~IEC 61180-2, *High-voltage test techniques for low-voltage equipment – Part 2: Test equipment*~~

~~IEC GUIDE 104, *The preparation of safety publications and the use of basic safety publications and group safety publications*~~

~~ISO/IEC GUIDE 51, *Safety aspects – Guidelines for their inclusion in standards*~~

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply (see Annex I for index of defined terms).

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at <https://www.electropedia.org/>
- ISO Online browsing platform: available at <https://www.iso.org/obp>

3.1 Parts and accessories

3.1.1

TERMINAL

component provided for the connection of a device (equipment) to external conductors

Note 1 to entry: TERMINALS can contain one or several contacts and the term includes sockets, pins, etc.

3.1.2

ENCLOSURE

part providing protection of a probe assembly against certain external influences and, in any direction, protection against direct contact

3.1.3

PROTECTIVE FINGERGUARD

part of the ENCLOSURE that indicates the limit of safe access and that reduces the risk of the OPERATOR touching HAZARDOUS LIVE parts

3.1.4

PROBE TIP

part of a probe assembly or accessory which ~~makes a connection to~~ can touch **5** the point being measured or tested

~~Note 1 to entry: The term "PROBE TIP" includes the conductive parts of the jaws or hooks of SPRING-LOADED CLIPS.~~

3.1.5

CONNECTOR

component which is attached to the PROBE WIRE, to connect the probe assembly to a TERMINAL of the equipment or to another probe assembly

3.1.6

REFERENCE CONNECTOR **6**

CONNECTOR for connection to a reference point

3.1.7

TOOL

external device, including a key or coin, used to aid a person performing a mechanical function

3.1.8

PROBE WIRE

flexible wire or cable used as part of the probe assembly or its accessories, consisting of one or more conductors and associated insulation

3.1.9

SPRING-LOADED CLIP

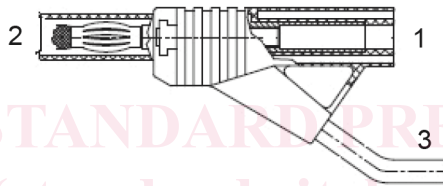
probe or probe accessory with one or more hooks or jaws forced by a spring to grip the part being measured or tested

3.1.10

STACKABLE CONNECTOR

CONNECTOR assembly which contains an additional TERMINAL

EXAMPLE Figure 1 is an example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL.



Key

- 1 TERMINAL for ADDITIONAL CONNECTOR [IEC 61010-031:2022](#)
- 2 CONNECTOR [standards.iteh.ai/catalog/standards/sist/096f8d8f-4592-499a-a290-feead86a3a05/iec-61010-031-2022](#)
- 3 PROBE WIRE

Figure 1 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL

3.2 Quantities

3.2.1

RATED ~~(condition or value)~~

RATED value

condition or quantity value assigned, generally by a manufacturer, for a specified operating condition of a component, device, or probe assembly

3.2.2

RATING

set of RATED values and operating conditions

[SOURCE: IEC 60050-151:2001, 151-16-11]

3.2.3

WORKING VOLTAGE

highest RMS value of the AC or DC voltage across any particular insulation which can continuously appear during NORMAL USE

Note 1 to entry: Transients and voltage fluctuations are not considered to be part of the WORKING VOLTAGE.

3.3 Tests

3.3.1

TYPE TEST

test of one or more samples of a probe assembly (or parts of a probe assembly) made to a particular design, to show that the design and construction meet the requirements of this document

Note 1 to entry: This is an ~~amplification~~ enlargement of the IEC 60050-151:2001, 151-16-16 definition to cover design as well as construction.

3.3.2

ROUTINE TEST

conformity test made on each individual item during or after manufacture

[SOURCE: IEC 60050-151:2001, 151-16-17]

3.4 Safety terms

3.4.1

ACCESSIBLE

able to be touched with a standard test finger or test pin, when used as specified in 7.2

3.4.2

HAZARDOUS LIVE

capable of rendering an electric shock or electric burn

3.4.3

HAZARD

potential source of harm

3.4.4

PROTECTIVE IMPEDANCE

component or assembly of components whose impedance, construction and reliability are suitable to provide protection against electric shock

3.4.5

NORMAL USE

operation, including stand-by, according to the instructions for use or for the obvious intended purpose

3.4.6

NORMAL CONDITION

condition in which all means for protection against HAZARDS are intact

3.4.7

SINGLE FAULT CONDITION **7**

condition in which one means for protection against a HAZARD is defective or one fault is present which could cause a HAZARD

Note 1 to entry: If a SINGLE FAULT CONDITION results unavoidably in one or more other fault conditions, all the failures are considered as one SINGLE FAULT CONDITION.

3.4.8

OPERATOR

person operating the probe assembly for its intended purpose

3.4.9

RESPONSIBLE BODY

individual or group responsible for the safe use and maintenance of probe assemblies